



Dependability of Emerging Computing Paradigms and Technologies in IoT-Oriented Circuits, Architectures and Algorithms

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Deadline for manuscript
submissions:

closed (30 September 2023)

Message from the Guest Editors

In recent decades, the incessant growing presence of smart applications in our daily lives has pushed the frenetic development of new devices which constitute the Internet of Things infrastructure (IoT). The undeniable need for energy efficiency in these devices is leading to the adoption of innovative computing paradigms—such as approximate computing, computation-in-memory, and neuromorphic computing—and emerging technologies—such as new nonvolatile memories (RRAM, MRAM, FeRAM, etc.). As we are heading toward a future where the ubiquitous presence of these devices will simplify and guide our daily actions, their dependability is of primary concern. This Special Issue focuses on aspects related to the dependability of these emerging computing paradigms and technologies in the context of IoT devices.

Keywords

- dependability
- reliability
- fault tolerance
- test
- verification
- energy efficiency
- emerging computing paradigms
- emerging technologies
- embedded IoT





an Open Access Journal by MDPI

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Message from the Editor-in-Chief

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